Application/Control No. Applicant(s)/Patent Under Reexamination 10/085,381 TERADA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Ahshik Kim 2876 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY 02-2001 US-6,189,783 Motomiya et al. 235/375 Α US-В US-С D US-US-Ε F US-US-G US-Н US-1 US-J Κ US-US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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